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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	CANbus, LINbus, SCI, SPI
Peripherals	DMA, POR, PWM, WDT
Number of I/O	79
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 33x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/spc5602df1mll3r

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1 Introduction

1.1 Document overview

This document describes the device features and highlights the important electrical and physical characteristics.

1.2 Description

These 32-bit automotive microcontrollers are a family of system-on-chip (SoC) devices designed to be central to the development of the next wave of central vehicle body controller, smart junction box, front module, peripheral body, door control and seat control applications.

This family is one of a series of next-generation integrated automotive microcontrollers based on the Power Architecture technology and designed specifically for embedded applications.

The advanced and cost-efficient e200z0h host processor core of this automotive controller family complies with the Power Architecture technology and only implements the VLE (variable-length encoding) APU (auxiliary processing unit), providing improved code density. It operates at speeds of up to 48 MHz and offers high performance processing optimized for low power consumption. It capitalizes on the available development infrastructure of current Power Architecture devices and is supported with software drivers, operating systems and configuration code to assist with the user's implementations.

The device platform has a single level of memory hierarchy and can support a wide range of on-chip static random access memory (SRAM) and internal flash memory.

Table 1. MPC5602D device comparison

Feature	Device			
	MPC5601DxLH	MPC5601DxLL	MPC5602DxLH	MPC5602DxLL
CPU	e200z0h			
Execution speed	Static – up to 48 MHz			
Code flash memory	128 KB		256 KB	
Data flash memory	64 KB (4 × 16 KB)			
SRAM	12 KB		16 KB	
eDMA	16 ch			
ADC (12-bit)	16 ch	33 ch	16 ch	33 ch
CTU	16 ch			
Total timer I/O[1] eMIOS	14 ch, 16-bit	28 ch, 16-bit	14 ch, 16-bit	28 ch, 16-bit
• Type X[2]	2 ch	5 ch	2 ch	5 ch
• Type Y[3]	—	9 ch	—	9 ch
• Type G[4]	7 ch	7 ch	7 ch	7 ch
• Type H[5]	4 ch	7 ch	4 ch	7 ch
SCI (LINFlex)	3			
SPI (DSPI)	2			
CAN (FlexCAN)	1			
GPIO[6]	45	79	45	79

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function[1]	Function	Peripheral	I/O direction[2]	Pad type	RESET configuration	Pin number	
								64 LQFP	100 LQFP
PB[15]	PCR[31]	AF0 AF1 AF2 AF3 —	GPIO[31] E0UC[7] — CS4_0 ADC1_X[3]	SIUL eMIOS_0 — DSPI_0 ADC	I/O I/O — O I	J	Tristate	42	67
Port C									
PC[0][6]	PCR[32]	AF0 AF1 AF2 AF3	GPIO[32] — TDI —	SIUL — JTAGC —	I/O — I —	M	Input, weak pull-up	59	87
PC[1][6]	PCR[33]	AF0 AF1 AF2 AF3	GPIO[33] — TDO —	SIUL — JTAGC —	I/O — O —	F	Tristate	54	82
PC[2]	PCR[34]	AF0 AF1 AF2 AF3 —	GPIO[34] SCK_1 — — EIRQ[5]	SIUL DSPI_1 — — SIUL	I/O I/O — — I	M	Tristate	50	78
PC[3]	PCR[35]	AF0 AF1 AF2 AF3 —	GPIO[35] CS0_1 MA[0] — EIRQ[6]	SIUL DSPI_1 ADC — SIUL	I/O I/O O — I	S	Tristate	49	77
PC[4]	PCR[36]	AF0 AF1 AF2 AF3 — —	GPIO[36] — — — SIN_1 EIRQ[18]	SIUL — — — DSPI_1 SIUL	I/O — — — I I	M	Tristate	62	92
PC[5]	PCR[37]	AF0 AF1 AF2 AF3 —	GPIO[37] SOUT_1 — — EIRQ[7]	SIUL DSPI_1 — — SIUL	I/O O — — I	M	Tristate	61	91
PC[6]	PCR[38]	AF0 AF1 AF2 AF3	GPIO[38] LIN1TX — —	SIUL LINFlex_1 — —	I/O O — —	S	Tristate	16	25

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function[1]	Function	Peripheral	I/O direction[2]	Pad type	RESET configuration	Pin number	
								64 LQFP	100 LQFP
PD[8]	PCR[56]	AF0 AF1 AF2 AF3 —	GPIO[56] — — — ADC1_P[12]	SIUL — — — ADC	I — — — I	I	Tristate	—	49
PD[9]	PCR[57]	AF0 AF1 AF2 AF3 —	GPIO[57] — — — ADC1_P[13]	SIUL — — — ADC	I — — — I	I	Tristate	—	56
PD[10]	PCR[58]	AF0 AF1 AF2 AF3 —	GPIO[58] — — — ADC1_P[14]	SIUL — — — ADC	I — — — I	I	Tristate	—	57
PD[11]	PCR[59]	AF0 AF1 AF2 AF3 —	GPIO[59] — — — ADC1_P[15]	SIUL — — — ADC	I — — — I	I	Tristate	—	58
PD[12]	PCR[60]	AF0 AF1 AF2 AF3 —	GPIO[60] CS5_0 E0UC[24] — ADC1_S[8]	SIUL DSPI_0 eMIOS_0 — ADC	I/O O I/O — I	J	Tristate	—	60
PD[13]	PCR[61]	AF0 AF1 AF2 AF3 —	GPIO[61] CS0_1 E0UC[25] — ADC1_S[9]	SIUL DSPI_1 eMIOS_0 — ADC	I/O I/O I/O — I	J	Tristate	—	62
PD[14]	PCR[62]	AF0 AF1 AF2 AF3 —	GPIO[62] CS1_1 E0UC[26] — ADC1_S[10]	SIUL DSPI_1 eMIOS_0 — ADC	I/O O I/O — I	J	Tristate	—	64
PD[15]	PCR[63]	AF0 AF1 AF2 AF3 —	GPIO[63] CS2_1 E0UC[27] — ADC1_S[11]	SIUL DSPI_1 eMIOS_0 — ADC	I/O O I/O — I	J	Tristate	—	66
Port E									

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function[1]	Function	Peripheral	I/O direction[2]	Pad type	RESET configuration	Pin number	
								64 LQFP	100 LQFP
PE[0]	PCR[64]	AF0 AF1 AF2 AF3 —	GPIO[64] E0UC[16] — — WKPU[6][3]	SIUL eMIOS_0 — — WKPU	I/O I/O — — I	S	Tristate	—	6
PE[1]	PCR[65]	AF0 AF1 AF2 AF3	GPIO[65] E0UC[17] — —	SIUL eMIOS_0 — —	I/O I/O — —	M	Tristate	—	8
PE[2]	PCR[66]	AF0 AF1 AF2 AF3 — —	GPIO[66] E0UC[18] — — EIRQ[21] SIN_1	SIUL eMIOS_0 — — SIUL DSPI_1	I/O I/O — — I I	M	Tristate	—	89
PE[3]	PCR[67]	AF0 AF1 AF2 AF3	GPIO[67] E0UC[19] SOUT_1 —	SIUL eMIOS_0 DSPI_1 —	I/O I/O O —	M	Tristate	—	90
PE[4]	PCR[68]	AF0 AF1 AF2 AF3 —	GPIO[68] E0UC[20] SCK_1 — EIRQ[9]	SIUL eMIOS_0 DSPI_1 — SIUL	I/O I/O I/O — I	M	Tristate	—	93
PE[5]	PCR[69]	AF0 AF1 AF2 AF3	GPIO[69] E0UC[21] CS0_1 MA[2]	SIUL eMIOS_0 DSPI_1 ADC	I/O I/O I/O O	M	Tristate	—	94
PE[6]	PCR[70]	AF0 AF1 AF2 AF3 —	GPIO[70] E0UC[22] CS3_0 MA[1] EIRQ[22]	SIUL eMIOS_0 DSPI_0 ADC SIUL	I/O I/O O O I	M	Tristate	—	95
PE[7]	PCR[71]	AF0 AF1 AF2 AF3 —	GPIO[71] E0UC[23] CS2_0 MA[0] EIRQ[23]	SIUL eMIOS_0 DSPI_0 ADC SIUL	I/O I/O O O I	M	Tristate	—	96
PE[8]	PCR[72]	AF0 AF1 AF2 AF3	GPIO[72] — E0UC[22] —	SIUL — eMIOS_0 —	I/O — I/O —	M	Tristate	—	9

Table 5. Functional port pin descriptions (continued)

Port pin	PCR	Alternate function[1]	Function	Peripheral	I/O direction[2]	Pad type	RESET configuration	Pin number	
								64 LQFP	100 LQFP
PE[9]	PCR[73]	AF0 AF1 AF2 AF3 —	GPIO[73] — E0UC[23] — WKPU[7][3]	SIUL — eMIOS_0 — WKPU	I/O — I/O — I	S	Tristate	—	10
PE[10]	PCR[74]	AF0 AF1 AF2 AF3 —	GPIO[74] — CS3_1 — EIRQ[10]	SIUL — DSPI_1 — SIUL	I/O — O — I	S	Tristate	—	11
PE[11]	PCR[75]	AF0 AF1 AF2 AF3 —	GPIO[75] E0UC[24] CS4_1 — WKPU[14][3]	SIUL eMIOS_0 DSPI_1 — WKPU	I/O I/O O — I	S	Tristate	—	13
PE[12]	PCR[76]	AF0 AF1 AF2 AF3 — —	GPIO[76] — — — ADC1_S[7] EIRQ[11]	SIUL — — — ADC SIUL	I/O — — — I I	S	Tristate	—	76
Port H									
PH[9][6]	PCR[121]	AF0 AF1 AF2 AF3	GPIO[121] — TCK —	SIUL — JTAGC —	I/O — I —	S	Input, weak pull-up	60	88
PH[10][6]	PCR[122]	AF0 AF1 AF2 AF3	GPIO[122] — TMS —	SIUL — JTAGC —	I/O — I —	S	Input, weak pull-up	53	81

1 Alternate functions are chosen by setting the values of the PCR.PA bitfields inside the SIUL module. PCR.PA = 00 → AF0; PCR.PA = 01 → AF1; PCR.PA = 10 → AF2; PCR.PA = 11 → AF3. This is intended to select the output functions; to use one of the input functions, the PCR.IBE bit must be written to '1', regardless of the values selected in the PCR.PA bitfields. For this reason, the value corresponding to an input only function is reported as "—".

2 Multiple inputs are routed to all respective modules internally. The input of some modules must be configured by setting the values of the PSMIO.PADSELx bitfields inside the SIUL module.

3 All WKPU pins also support external interrupt capability. See "wakeup unit" chapter of the device reference manual for further details.

4 NMI has higher priority than alternate function. When NMI is selected, the PCR.AF field is ignored.

5 "Not applicable" because these functions are available only while the device is booting. Refer to "BAM" chapter of the device reference manual for details.

NOTE

SRAM data retention is guaranteed with V_{DD_LV} not below 1.08 V.

4.6 Thermal characteristics

4.6.1 Package thermal characteristics

Table 13. LQFP thermal characteristics[1]

Symbol		C	Parameter	Conditions[2]		Value	Unit
$R_{\theta JA}$	CC	D	Thermal resistance, junction-to-ambient natural convection[3]	Single-layer board —1s	LQFP64	72.1	°C/W
					LQFP100	65.2	
				Four-layer board — 2s2p	LQFP64	57.3	
					LQFP100	51.8	
$R_{\theta JB}$	CC	D	Thermal resistance, junction-to-board[4]	Four-layer board — 2s2p	LQFP64	44.1	°C/W
					LQFP100	41.3	
$R_{\theta JC}$	CC	D	Thermal resistance, junction-to-case[5]	Single-layer board — 1s	LQFP64	26.5	°C/W
					LQFP100	23.9	
				Four-layer board — 2s2p	LQFP64	26.2	
					LQFP100	23.7	
Ψ_{JB}	CC	D	Junction-to-board thermal characterization parameter, natural convection	Single-layer board — 1s	LQFP64	41	°C/W
					LQFP100	41.6	
				Four-layer board — 2s2p	LQFP64	43	
					LQFP100	43.4	
Ψ_{JC}	CC	D	Junction-to-case thermal characterization parameter, natural convection	Single-layer board — 1s	LQFP64	11.5	°C/W
					LQFP100	10.4	
				Four-layer board — 2s2p	LQFP64	11.1	
					LQFP100	10.2	

1 Thermal characteristics are targets based on simulation that are subject to change per device characterization.

2 V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C

3 Junction-to-ambient thermal resistance determined per JEDEC JESD51-3 and JESD51-7. Thermal test board meets JEDEC specification for this package. When Greek letters are not available, the symbols are typed as R_{thJA}.

4 Junction-to-board thermal resistance determined per JEDEC JESD51-8. Thermal test board meets JEDEC specification for the specified package. When Greek letters are not available, the symbols are typed as R_{thJB}.

5 Junction-to-case at the top of the package determined using MIL-STD 883 Method 1012.1. The cold plate temperature is used for the case temperature. Reported value includes the thermal resistance of the interface layer. When Greek letters are not available, the symbols are typed as R_{thJC}.

4.6.2 Power considerations

The average chip-junction temperature, T_J, in degrees Celsius, may be calculated using Equation 1:

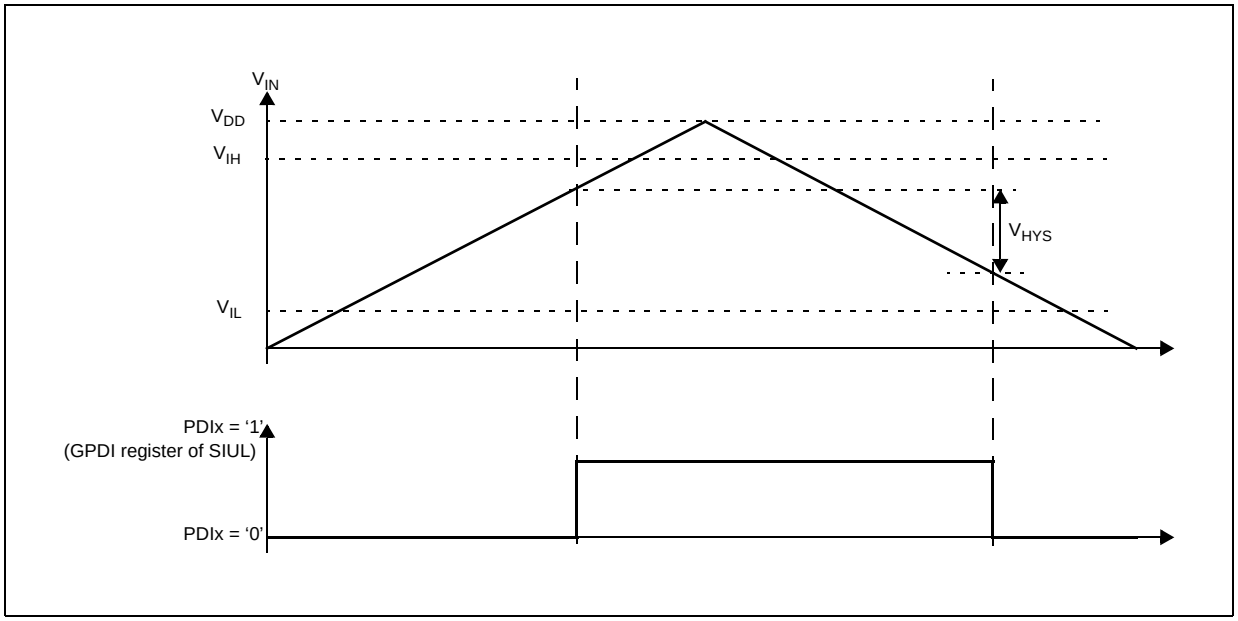

Figure 4. Input DC electrical characteristics definition

Table 14. I/O input DC electrical characteristics

Symbol		C	Parameter	Conditions[1]		Value			Unit
						Min	Typ	Max	
V_{IH}	SR	P	Input high level CMOS (Schmitt Trigger)	—		$0.65V_{DD}$	—	$V_{DD}+0.4$	V
V_{IL}	SR	P	Input low level CMOS (Schmitt Trigger)	—		–0.4	—	$0.35V_{DD}$	V
V_{HYS}	CC	C	Input hysteresis CMOS (Schmitt Trigger)	—		$0.1V_{DD}$	—	—	V
I_{LKG}	CC	D	Digital input leakage	No injection on adjacent pin	T_A = –40 °C	—	2	200	nA
		D			T_A = 25 °C	—	2	200	
		D			T_A = 85 °C	—	5	300	
		D			T_A = 105 °C	—	12	500	
		P			T_A = 125 °C	—	70	1000	
W_{FI}[2]	SR	P	Digital input filtered pulse	—		—	—	40	ns
W_{NFI}[(2)]	SR	P	Digital input not filtered pulse	—		1000	—	—	ns

1 V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C, unless otherwise specified

2 In the range from 40 to 1000 ns, pulses can be filtered or not filtered, according to operating temperature and voltage.

4.7.3 I/O output DC characteristics

The following tables provide DC characteristics for bidirectional pads:

- Table 15 provides weak pull figures. Both pull-up and pull-down resistances are supported.

- Table 16 provides output driver characteristics for I/O pads when in SLOW configuration.
- Table 17 provides output driver characteristics for I/O pads when in MEDIUM configuration.

Table 15. I/O pull-up/pull-down DC electrical characteristics

Symbol		C	Parameter	Conditions[1]		Value			Unit
						Min	Typ	Max	
$\|I_{WPU}\|$	CC	P	Weak pull-up current absolute value	$V_{IN} = V_{IL}$, V_{DD} = 5.0 V ± 10%	PAD3V5V = 0	10	—	150	µA
		C			PAD3V5V = 1[2]	10	—	250	
		P		$V_{IN} = V_{IL}$, V_{DD} = 3.3 V ± 10%	PAD3V5V = 1	10	—	150	
$\|I_{WPD}\|$	CC	P	Weak pull-down current absolute value	$V_{IN} = V_{IH}$, V_{DD} = 5.0 V ± 10%	PAD3V5V = 0	10	—	150	µA
		C			PAD3V5V = 1(2)	10	—	250	
		P		$V_{IN} = V_{IH}$, V_{DD} = 3.3 V ± 10%	PAD3V5V = 1	10	—	150	

1 V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C, unless otherwise specified.

2 The configuration PAD3V5 = 1 when V_{DD} = 5 V is only a transient configuration during power-up. All pads but RESET are configured in input or in high impedance state.

Table 16. SLOW configuration output buffer electrical characteristics

Symbol		C	Parameter	Conditions[1]		Value			Unit
						Min	Typ	Max	
V_{OH}	CC	P	Output high level SLOW configuration	Push Pull	I_{OH} = –2 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 0 (recommended)	0.8V_{DD}	—	—	V
		C			I_{OH} = –2 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 1[2]	0.8V_{DD}	—	—	
		C			I_{OH} = –1 mA, V_{DD} = 3.3 V ± 10%, PAD3V5V = 1 (recommended)	V_{DD} – 0.8	—	—	
V_{OL}	CC	P	Output low level SLOW configuration	Push Pull	I_{OL} = 2 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 0 (recommended)	—	—	0.1V_{DD}	V
		C			I_{OL} = 2 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 1(2)	—	—	0.1V_{DD}	
		C			I_{OL} = 1 mA, V_{DD} = 3.3 V ± 10%, PAD3V5V = 1 (recommended)	—	—	0.5	

1 V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C, unless otherwise specified

2 The configuration PAD3V5 = 1 when V_{DD} = 5 V is only a transient configuration during power-up. All pads but RESET are configured in input or in high impedance state.

Table 21. I/O weight[1] (continued)

Pad	100 LQFP/64 LQFP			
	Weight 5 V		Weight 3.3 V	
	SRC[2] = 0	SRC = 1	SRC = 0	SRC = 1
PD[5]	1%	1%	1%	1%
PD[6]	1%	1%	1%	1%
PD[7]	1%	1%	1%	1%
PD[8]	1%	1%	1%	1%
PB[4]	1%	1%	1%	1%
PB[5]	1%	1%	1%	1%
PB[6]	1%	1%	1%	1%
PB[7]	1%	1%	1%	1%
PD[9]	1%	1%	1%	1%
PD[10]	1%	1%	1%	1%
PD[11]	1%	1%	1%	1%
PB[11]	9%	9%	11%	11%
PD[12]	8%	8%	10%	10%
PB[12]	8%	8%	10%	10%
PD[13]	8%	8%	9%	9%
PB[13]	8%	8%	9%	9%
PD[14]	7%	7%	9%	9%
PB[14]	7%	7%	8%	8%
PD[15]	7%	7%	8%	8%
PB[15]	6%	6%	7%	7%
PA[3]	6%	6%	7%	7%
PA[7]	4%	4%	5%	5%
PA[8]	4%	4%	5%	5%
PA[9]	4%	4%	5%	5%
PA[10]	5%	5%	6%	6%
PA[11]	5%	5%	6%	6%
PE[12]	5%	5%	6%	6%
PC[3]	5%	5%	6%	6%
PC[2]	5%	7%	6%	6%
PA[5]	5%	6%	5%	6%
PA[6]	4%	4%	5%	5%
PC[1]	5%	17%	4%	12%

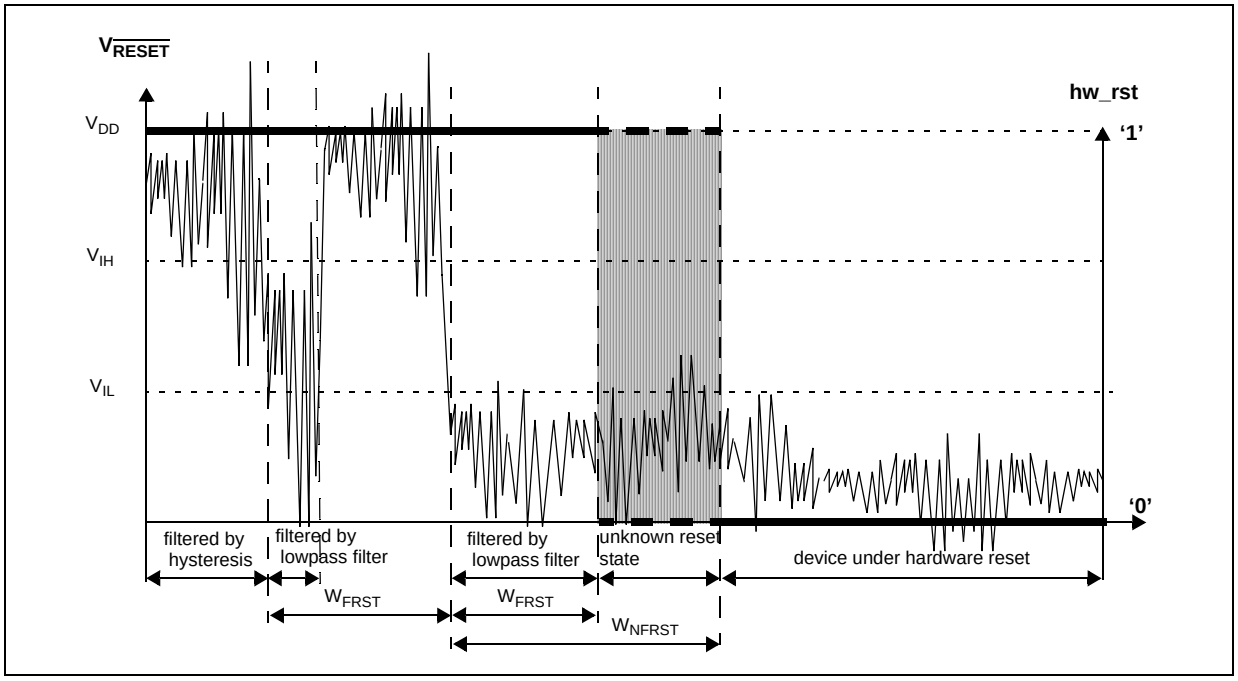

Figure 6. Noise filtering on reset signal

Table 22. Reset electrical characteristics

Symbol		C	Parameter	Conditions[1]	Value			Unit
					Min	Typ	Max	
V_{IH}	SR	P	Input High Level CMOS (Schmitt Trigger)	—	$0.65V_{DD}$	—	V_{DD} + 0.4	V
V_{IL}	SR	P	Input low Level CMOS (Schmitt Trigger)	—	–0.4	—	$0.35V_{DD}$	V
V_{HYS}	CC	C	Input hysteresis CMOS (Schmitt Trigger)	—	$0.1V_{DD}$	—	—	V
V_{OL}	CC	P	Output low level	Push Pull, I_{OL} = 2 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 0 (recommended)	—	—	$0.1V_{DD}$	V
				Push Pull, I_{OL} = 1 mA, V_{DD} = 5.0 V ± 10%, PAD3V5V = 1[2]	—	—	$0.1V_{DD}$	
				Push Pull, I_{OL} = 1 mA, V_{DD} = 3.3 V ± 10%, PAD3V5V = 1 (recommended)	—	—	0.5	

— LV_CFLA: Low voltage supply for code flash module. It is supplied with dedicated ballast and shorted to LV_COR through double bonding.
— LV_DFLA: Low voltage supply for data flash module. It is supplied with dedicated ballast and shorted to LV_COR through double bonding.
— LV_PLL: Low voltage supply for FMPLL. It is shorted to LV_COR through double bonding.

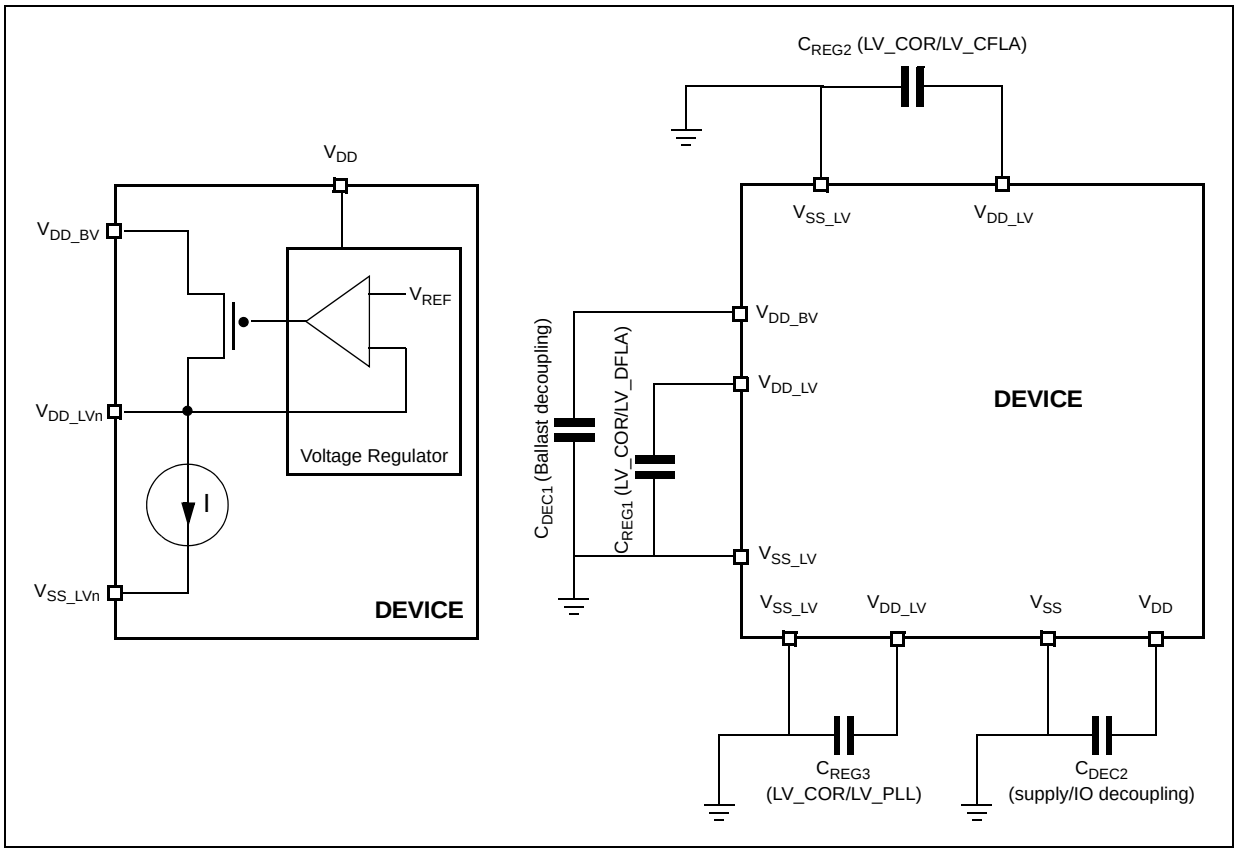

Figure 7. Voltage regulator capacitance connection

The internal voltage regulator requires external capacitance (C_{REGn}) to be connected to the device in order to provide a stable low voltage digital supply to the device. Capacitances should be placed on the board as near as possible to the associated pins. Care should also be taken to limit the serial inductance of the board to less than 5 nH.

Each decoupling capacitor must be placed between each of the three V_{DD_LV}/V_{SS_LV} supply pairs to ensure stable voltage (see Section 4.5, Recommended operating conditions).

Table 23. Voltage regulator electrical characteristics

Symbol		C	Parameter	Conditions[1]	Value			Unit
					Min	Typ	Max	
C_{REGn}	SR	—	Internal voltage regulator external capacitance	—	200	—	500	nF
R_{REG}	SR	—	Stability capacitor equivalent serial resistance	Range: 10 kHz to 20 MHz	—	—	0.2	Ω

Table 26. Program and erase specifications (code flash)

Symbol		C	Parameter	Value				Unit
				Min	Typ[1]	Initial max[2]	Max[3]	
$t_{dwprogram}$	CC	C	Double word (64 bits) program time[4]	—	22	50	500	µs
$t_{16Kpperase}$	CC	C	16 KB block preprogram and erase time	—	300	500	5000	ms
$t_{32Kpperase}$	CC	C	32 KB block preprogram and erase time	—	400	600	5000	ms
$t_{128Kpperase}$	CC	C	128 KB block preprogram and erase time	—	800	1300	7500	ms
t_{esus}	CC	C	Erase suspend latency	—	—	30	30	µs

1 Typical program and erase times assume nominal supply values and operation at 25 °C. All times are subject to change pending device characterization.

2 Initial factory condition: < 100 program/erase cycles, 25 °C, typical supply voltage.

3 The maximum program and erase times occur after the specified number of program/erase cycles. These maximum values are characterized but not guaranteed.

4 Actual hardware programming times. This does not include software overhead.

Table 27. Program and erase specifications (data flash)

Symbol		C	Parameter	Value				Unit
				Min	Typ[1]	Initial max[2]	Max[3]	
$t_{swprogram}$	CC	C	Single word (32 bits) program time[4]	—	30	70	300	µs
$t_{16Kpperase}$	CC	C	16 KB block preprogram and erase time	—	700	800	1500	ms
t_{Bank_D}	CC	C	64 KB block preprogram and erase time	—	1900	2300	4800	ms

1 Typical program and erase times assume nominal supply values and operation at 25 °C. All times are subject to change pending device characterization.

2 Initial factory condition: < 100 program/erase cycles, 25 °C, typical supply voltage.

3 The maximum program and erase times occur after the specified number of program/erase cycles. These maximum values are characterized but not guaranteed.

4 Actual hardware programming times. This does not include software overhead.

Table 35. Crystal description

Nominal frequency (MHz)	NDK crystal reference	Crystal equivalent series resistance (ESR) Ω	Crystal motional capacitance (C_m) fF	Crystal motional inductance (L_m) mH	Load on xtalin/xtalout $C_1 = C_2$ (pF)[1]	Shunt capacitance between xtalout and xtalin C0[2] (pF)
4	NX8045GB	300	2.68	591.0	21	2.93
8	NX5032GA	300	2.46	160.7	17	3.01
10		150	2.93	86.6	15	2.91
12		120	3.11	56.5	15	2.93
16		120	3.90	25.3	10	3.00

1 The values specified for C1 and C2 are the same as used in simulations. It should be ensured that the testing includes all the parasitics (from the board, probe, crystal, etc.) as the AC / transient behavior depends upon them.

2 The value of C0 specified here includes 2 pF additional capacitance for parasitics (to be seen with bond-pads, package, etc.).

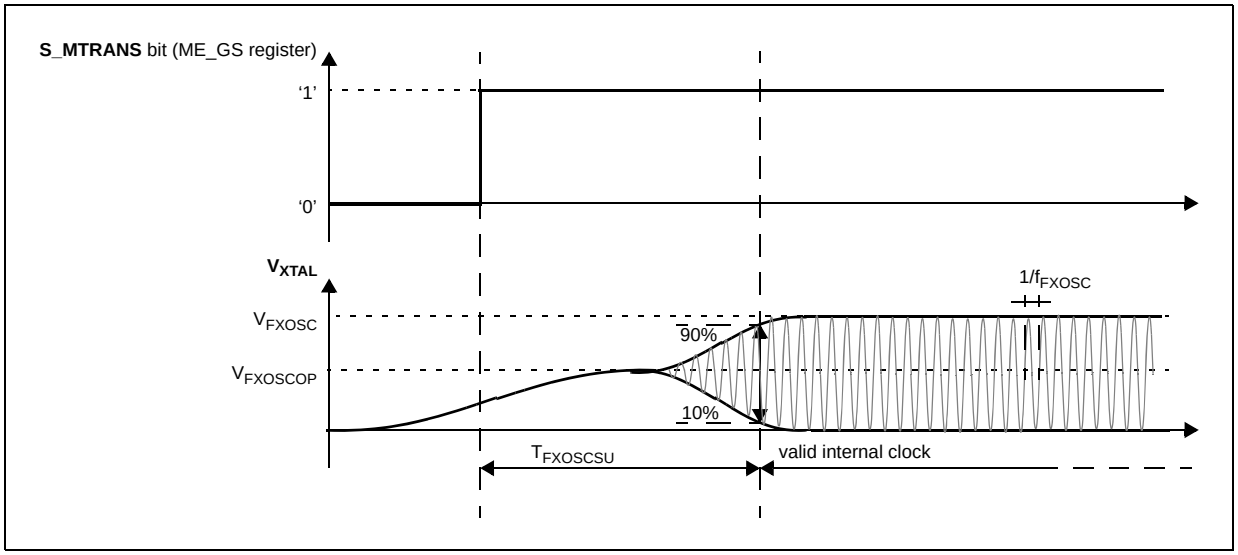

Figure 10. Fast external crystal oscillator (4 to 16 MHz) timing diagram

Table 36. Fast external crystal oscillator (4 to 16 MHz) electrical characteristics

Symbol		C	Parameter	Conditions[1]	Value			Unit
					Min	Typ	Max	
f_{FXOSC}	SR	—	Fast external crystal oscillator frequency	—	4.0	—	16.0	MHz
g_{mFXOSC}	CC	C	Fast external crystal oscillator transconductance	V_{DD} = 3.3 V ± 10%, PAD3V5V = 1 OSCILLATOR_MARGIN = 0	2.2	—	8.2	mA/V
	CC	P		V_{DD} = 5.0 V ± 10%, PAD3V5V = 0 OSCILLATOR_MARGIN = 0	2.0	—	7.4	
	CC	C		V_{DD} = 3.3 V ± 10%, PAD3V5V = 1 OSCILLATOR_MARGIN = 1	2.7	—	9.7	
	CC	C		V_{DD} = 5.0 V ± 10%, PAD3V5V = 0 OSCILLATOR_MARGIN = 1	2.5	—	9.2	
V_{FXOSC}	CC	T	Oscillation amplitude at EXTAL	f_{OSC} = 4 MHz, OSCILLATOR_MARGIN = 0	1.3	—	—	V
				f_{OSC} = 16 MHz, OSCILLATOR_MARGIN = 1	1.3	—	—	
$V_{FXOSCOP}$	CC	P	Oscillation operating point	—	—	0.95		V
I_{FXOSC}[2]	CC	T	Fast external crystal oscillator consumption	—	—	2	3	mA
$t_{FXOSCSU}$	CC	T	Fast external crystal oscillator start-up time	f_{OSC} = 4 MHz, OSCILLATOR_MARGIN = 0	—	—	6	ms
				f_{OSC} = 16 MHz, OSCILLATOR_MARGIN = 1	—	—	1.8	
V_{IH}	SR	P	Input high level CMOS (Schmitt Trigger)	Oscillator bypass mode	$0.65V_{DD}$	—	V_{DD}+0.4	V
V_{IL}	SR	P	Input low level CMOS (Schmitt Trigger)	Oscillator bypass mode	–0.4	—	$0.35V_{DD}$	V

1 V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = –40 to 125 °C, unless otherwise specified

2 Stated values take into account only analog module consumption but not the digital contributor (clock tree and enabled peripherals)

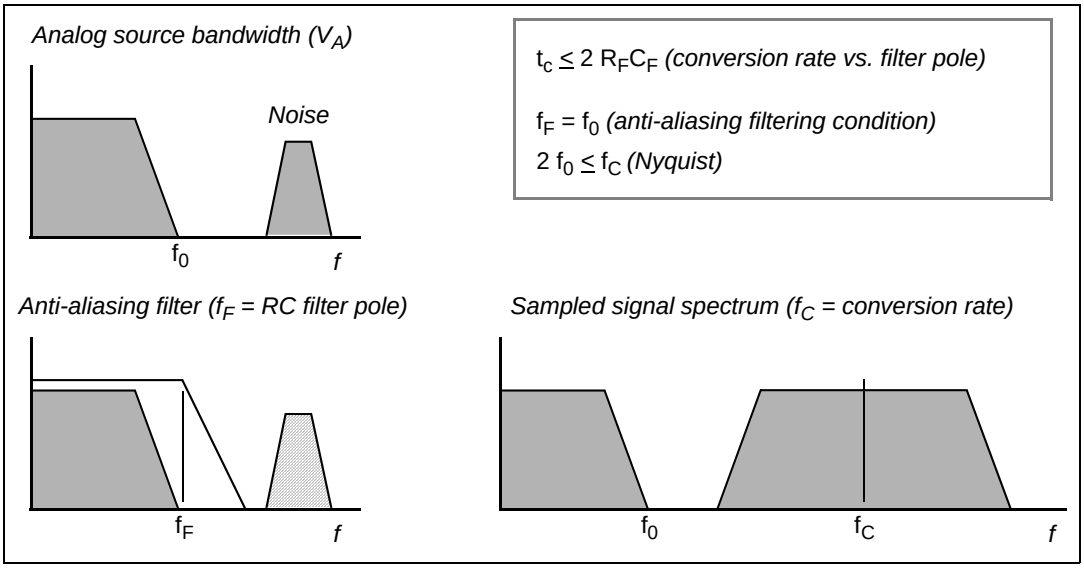

Figure 15. Spectral representation of input signal

Calling f_0 the bandwidth of the source signal (and as a consequence the cut-off frequency of the anti-aliasing filter, f_F), according to the Nyquist theorem the conversion rate f_C must be at least $2f_0$; it means that the constant time of the filter is greater than or at least equal to twice the conversion period (t_c). Again the conversion period t_c is longer than the sampling time t_s, which is just a portion of it, even when fixed channel continuous conversion mode is selected (fastest conversion rate at a specific channel): in conclusion it is evident that the time constant of the filter $R_F C_F$ is definitively much higher than the sampling time t_s, so the charge level on C_S cannot be modified by the analog signal source during the time in which the sampling switch is closed.

The considerations above lead to impose new constraints on the external circuit, to reduce the accuracy error due to the voltage drop on C_S; from the two charge balance equations above, it is simple to derive Equation 11 between the ideal and real sampled voltage on C_S:

Eqn. 11

$$\frac{V_{A2}}{V_A} = \frac{C_{P1} + C_{P2} + C_F}{C_{P1} + C_{P2} + C_F + C_S}$$

From this formula, in the worst case (when V_A is maximum, that is for instance 5 V), assuming to accept a maximum error of half a count, a constraint is evident on C_F value:

Eqn. 12

$$C_F > 2048 \bullet C_S$$

4.17.3 ADC electrical characteristics

Table 40. ADC input leakage current

Symbol		C	Parameter	Conditions		Value			Unit
						Min	Typ	Max	
I_{LKG}	CC	C	Input leakage current	T_A = –40 °C	No current injection on adjacent pin	—	1	—	nA
		C		T_A = 25 °C		—	1	—	
		C		T_A = 105 °C		—	8	200	
		P		T_A = 125 °C		—	45	400	

Table 41. ADC conversion characteristics

Symbol		C	Parameter	Conditions[1]	Value			Unit
					Min	Typ	Max	
V_{SS_ADC}	SR	—	Voltage on VSS_HV_ADC (ADC reference) pin with respect to ground (V_{SS})[2]	—	–0.1	—	0.1	V
V_{DD_ADC}	SR	—	Voltage on VDD_HV_ADC pin (ADC reference) with respect to ground (V_{SS})	—	V_{DD} – 0.1	—	V_{DD} + 0.1	V
V_{AINx}	SR	—	Analog input voltage[3]	—	V_{SS_ADC} – 0.1	—	V_{DD_ADC} + 0.1	V
f_{ADC}	SR	—	ADC analog frequency	V_{DD} = 5.0 V	3.33	—	32 + 4%	MHz
				V_{DD} = 3.3 V	3.33	—	20 + 4%	
Δ_{ADC_SYS}	SR	—	ADC clock duty cycle (ipg_clk)	ADCLKSEL = 1[4]	45	—	55	%
t_{ADC_PU}	SR	—	ADC power up delay	—	—	—	1.5	µs
t_s	CC	T	Sampling time[5] V_{DD} = 3.3 V	f_{ADC} = 20 MHz, INPSAMP = 12	600	—	—	ns
				f_{ADC} = 3.33 MHz, INPSAMP = 255	—	—	76.2	µs
		T	Sampling time(5) V_{DD} = 5.0 V	f_{ADC} = 24 MHz, INPSAMP = 13	500	—	—	ns
				f_{ADC} = 3.33 MHz, INPSAMP = 255	—	—	76.2	µs

4.18.3 JTAG characteristics

Table 44. JTAG characteristics

No.	Symbol		C	Parameter	Value			Unit
					Min	Typ	Max	
1	t_{JCYC}	CC	D	TCK cycle time	83.33	—	—	ns
2	t_{TDIS}	CC	D	TDI setup time	15	—	—	ns
3	t_{TDIH}	CC	D	TDI hold time	5	—	—	ns
4	t_{TMSS}	CC	D	TMS setup time	15	—	—	ns
5	t_{TMSH}	CC	D	TMS hold time	5	—	—	ns
6	t_{TDOV}	CC	D	TCK low to TDO valid	—	—	49	ns
7	t_{TDOI}	CC	D	TCK low to TDO invalid	6	—	—	ns

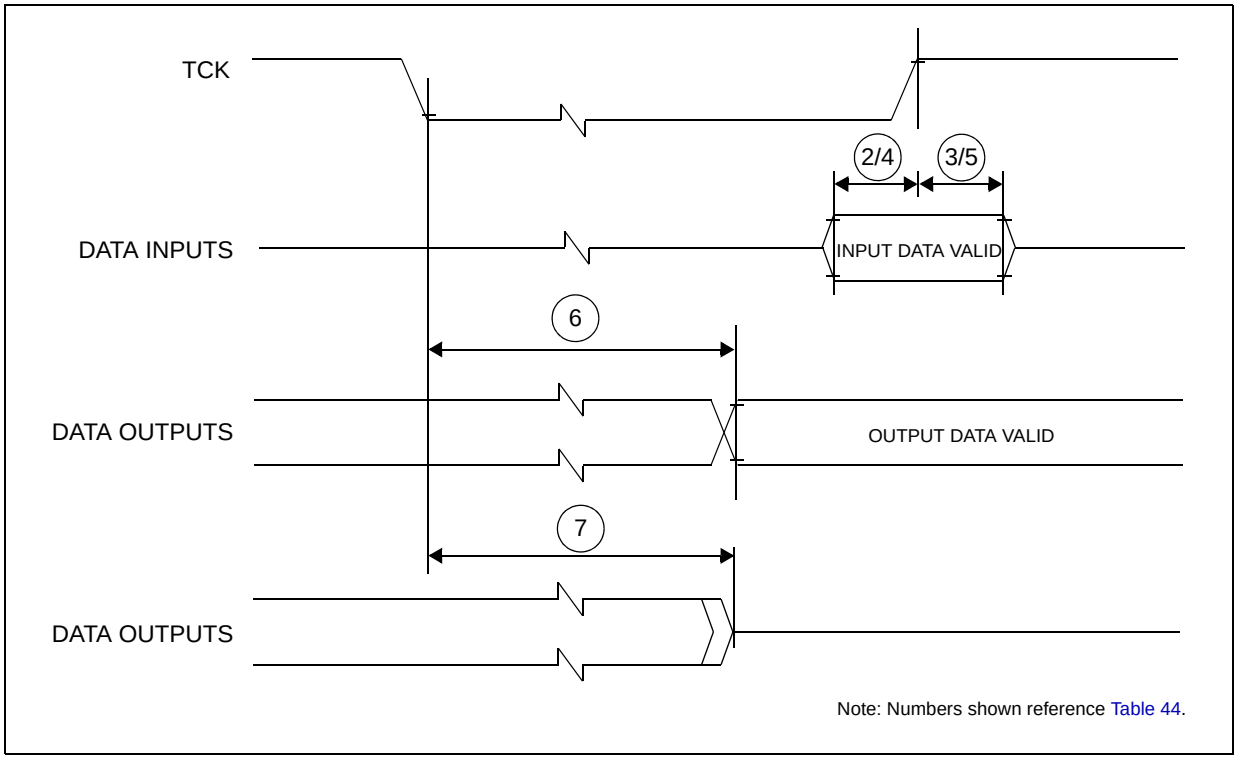

Figure 25. Timing diagram – JTAG boundary scan

5 Package characteristics

5.1 Package mechanical data

5.1.1 100 LQFP

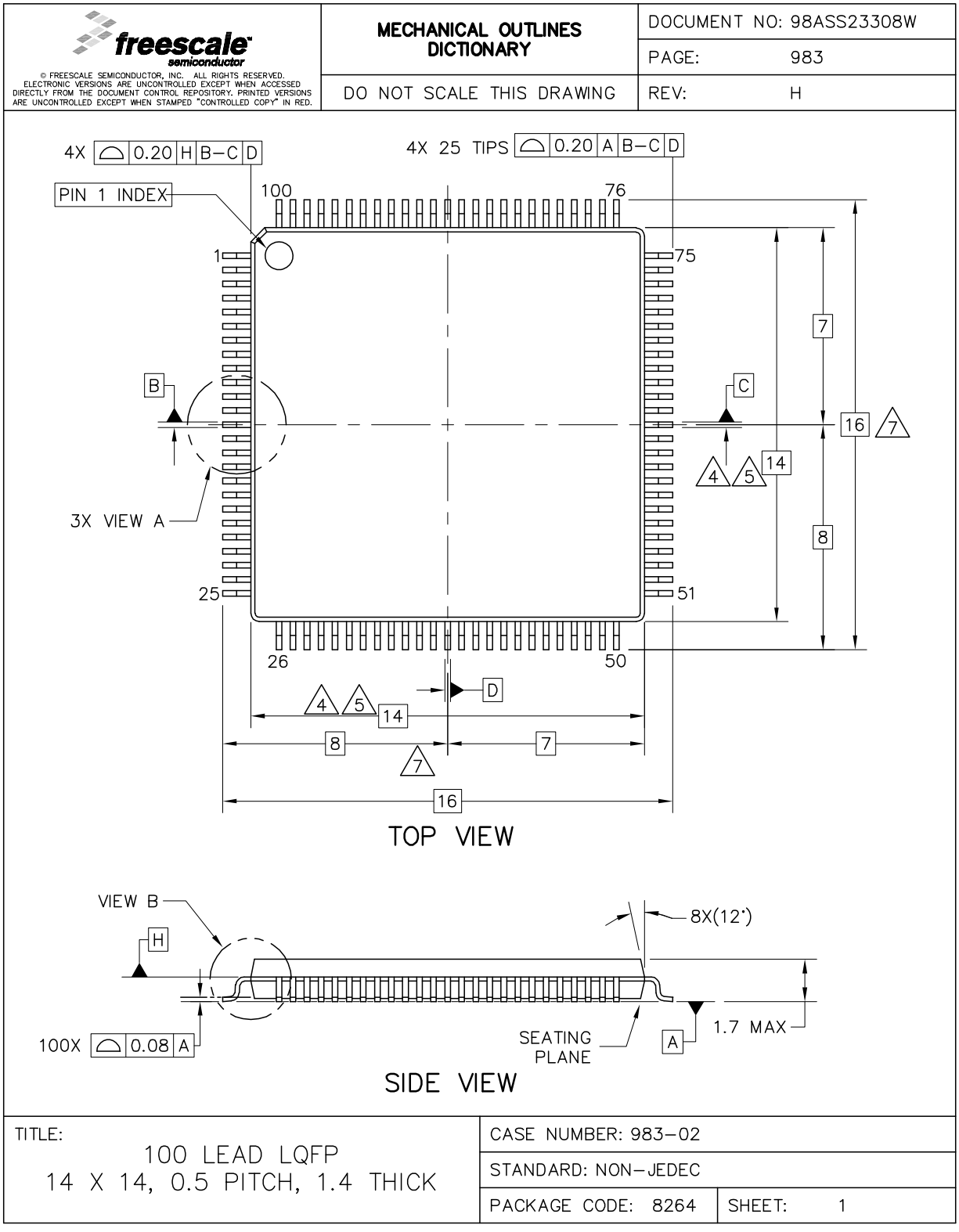

Figure 26. 100 LQFP package mechanical drawing (Part 1 of 3)

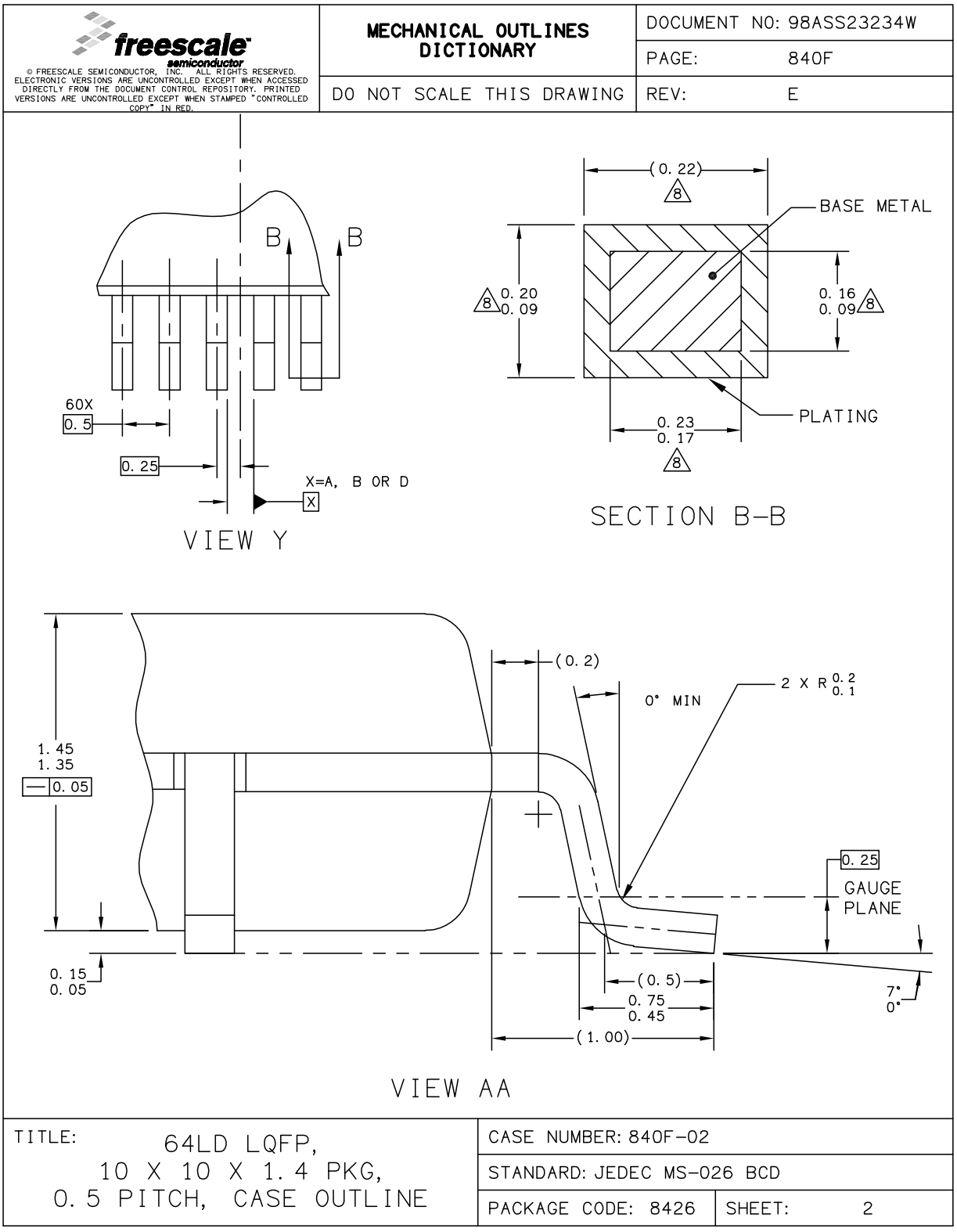

Figure 30. 64 LQFP mechanical drawing (part 2 of 3)